Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/643,254	CRATHER ET AL.
Examiner	Art Unit
Dimple N. Bodawala	1722

	SEARCHED				
Class	Subclass	Date	Examiner		
425	8,67,68, 308-311	1/17/2007	DB		
425	313,316	1/17/2007	DB		
425	382R,464	1/17/2007	DB		
264	8,37.12,	1/17/2007	DB		
264	37.18	1/17/2007	DB		
264	37.19	1/17/2007	DB		
264	37.2	1/17/2007	DB		
264	142,179	1/17/2007	DB		
264	178R	1/17/2007	DB		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEA		")
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